Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/647,672	HAN, SHERWIN	
Examiner	Art Unit	
Joon H. Hwang	2166	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor searched see search history printout(s)	6/1/2006	JH		
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